



**SDI Review Form 1.6**

Journal Name:	<a href="#">Physical Review &amp; Research International</a>
Manuscript Number:	<b>MS: 2013_PRRI_5907</b>
Title of the Manuscript:	<b>Evidence for negative electron affinity in laser irradiated ZnTe thin films</b>
Type of the Article	<i>Research Paper</i>

**General guideline for Peer Review process:**

This journal's peer review policy states that **NO** manuscript should be rejected only on the basis of '**lack of Novelty**', provided the manuscript is scientifically robust and technically sound.

To know the complete guideline for Peer Review process, reviewers are requested to visit this link:

(<http://www.sciencedomain.org/page.php?id=sdi-general-editorial-policy#Peer-Review-Guideline>)



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### PART 1: Review Comments

	Reviewer's comment	Author's comment (if agreed with reviewer, correct the manuscript and highlight that part in the manuscript. It is mandatory that authors should write his/her feedback here)
<b>Compulsory</b> REVISION comments	<p>Authors show interesting stripes and grooves formed by rastering laser beam, but how to do it? Pattern was mentioned in Line 56. What is the column dimension? Is it the same with the stripe dimension observed in SEM results?</p> <p>Current maps in Fig.5 show different profiles with different bias. Are they taken in the same area. ZnTe and Te areas should be different with a negative bias.</p> <p>Why no stripe like features in Fig.2 (c) and (d)?</p>	<p>A detailed description of the patterning process is now included on page line 56 onwards (highlighted in yellow colour in the text. Stripes and columns are the same. Hence for consistency we have used the word "stripes" only in the entire manuscript.</p> <p>Current maps in Fig. 5 are recorded at same position (area) with different bias. During negative bias, Schottky diode is formed between tip and film is in reverse bias condition so it is not possible to observe distinct features of ZnTe and Te. This is already explained from line no 299-308 (highlighted in yellow)</p> <p>Fig. 2 (c) and (d) are high resolution images, these images are zoomed over the stripes so actual stripe cannot be seen.</p>
<b>Minor</b> REVISION comments	Grammar errors should be corrected carefully, e.g. Line.288, Line.366. The scale bar note is too small in SEM pictures.	<p>All language related errors have been corrected throughout the paper.</p> <p>The SEM scale bars have now been enlarged.</p>
<b>Optional/General</b> comments	The XRD curve can be improved by longer scanning time. The noise level is high in this XRD pattern.	The XRD curve has been smoothened now so that the peaks are now visible.